

Wednesday, September 28

Poster Session (15:00-17:00) Multi-Purpose Hall and 102

All poster presenters must give the short oral presentations in Short Presentation Session scheduled on September 28, 11:00 - 12:00.
Each Area Session Room; see program Time Table

01: Advanced LSI Processing & Materials Science

(14 papers)

PS-1-01

Structural and Electrical Characterization of Epitaxial Ge Thin Film on Si (001) Formed by Sputtering

[◦]S. Otsuka¹, T. Mori¹, Y. Morita¹, N. Uchida¹, Y. Liu¹, S. O'uchi¹, H. Fuketa¹, S. Migita¹, M. Masahara¹, T. Matsukawa¹, ¹AIST (Japan)

PS-1-02

Growth of Heavily Doped n-Ge Epitaxial Layer by *In situ* Phosphorus-doping with Low-temperature Metal-Organic Chemical Vapor Deposition

[◦]S. Ike^{1,2}, W. Takeuchi¹, O. Nakatsuka¹, S. Zaima^{1,3}, ¹Graduate School of Eng., Nagoya Univ. (Japan), ²Research Fellow of JSPS (Japan), ³IMaSS, Nagoya Univ. (Japan)

PS-1-03

Formation Technology of Flat Surface after Selective-Epitaxial-Growth on Ion-implanted (100) Oriented Thin SOI Wafers

[◦]K. Furukawa¹, A. Teramoto¹, R. Kuroda¹, T. Suwa¹, K. Hashimoto¹, S. Sugawa¹, D. Suzuki², Y. Chiba², K. Ishii², A. Shimizu², K. Hasebe², ¹Tohoku Univ. (Japan), ²Tokyo Electron Tohoku Ltd. (Japan)

PS-1-04

Impact of Si_xGe_{1-x}Sn_y Interlayer on Reduction in Schottky Barrier Height of Metal/n-Ge Contact

[◦]A. Suzuki^{1,2}, S. Toda¹, O. Nakatsuka¹, M. Sakashita¹, S. Zaima^{1,3}, ¹Graduate School of Eng., Nagoya Univ. (Japan), ²Research Fellow of JSPS (Japan), ³IMaSS, Nagoya Univ. (Japan)

PS-1-05

Self-Aligned Deposition of Source/Drain Contact Metal with Electrodeposition Technique for High Performance Schottky Barrier Ge MOSFETs Fabrication

[◦]D. Zhai¹, J. Jiang^{1,2}, J. Li¹, X. Yu¹, R. Zhang¹, Y. Zhao¹, ¹Zhejiang Univ. (China), ²The:51th Res. Inst. of China Electronics Tech. Group Corp. (China)

PS-1-06

Influence of Low Thermal Budget Plasma Oxidation and Millisecond Laser Anneal on Gate Stack Reliability in view of 3D Sequential Integration

[◦]C.-M.V. Lu^{1,2}, C. Fenouillet-Béranger¹, R. Gassilloud¹, H. Graoui³, D. Larmagnac⁴, S. Sharma³, X. Garros³, C. Leroux¹, A. Toffoli¹, G. Romano^{1,2}, R. Kies¹, N. Rambal¹, M.-P. Samson², B. Previtali¹, C. Guedj¹, N. Bernier¹, S. Kerdiles¹, L. Brunet¹, P. Batude¹, T. Skotnicki², M. Vinet¹, ¹CEA-LETI (France), ²STMicroelectronics (France), ³Applied Materials Inc. (USA), ⁴Applied Materials France (France)

PS-1-07

Integration of Low Temperature 480°C SiOCN as Offset Spacer in view of 3D Sequential Integration

[◦]C.-M.V. Lu^{1,2}, C. Fenouillet-Béranger¹, C. Bout¹, A. Roule¹, V. Beugin¹, J. Fort³, C. Arvet², N. Posseme¹, V. Loup¹, P. Besson², M.-P. Samson², B. Previtali¹, C. Tabone¹, A. Michallet², N. Rochat¹, D. Benoit², F. Pierre¹, L. Brunet¹, P. Batude¹, T. Skotnicki², M. Vinet¹, ¹CEA-LETI (France), ²STMicroelectronics (France), ³Applied Materials France (France)

PS-1-08

Enhanced Electrical and Reliability Characteristics in Ge p-MOSFETs by In-situ Plasma Treatments and Capping Hf/Zr on Interfacial Layers

[◦]T. Huang¹, C. Hsu¹, K.S. Chang-Liao¹, Y. Hsu¹, C. Huang¹, Y. Li¹, ¹National Tsing Hua Univ. (Taiwan)

PS-1-09

Novel GeO₂ Interface Layer Engineering by Ultra Low Power Microwave Plasma Oxidation

[◦]K. Shiraga¹, J. Miyahara¹, G. Nakamura¹, Y. Fujino¹, K. Akiyama¹, K. Tapiro¹, T. Harada¹, E. Hara¹, A. Tamihara¹, N. Yamamoto¹, Y. Hirota¹, T. Kaitsuka¹, T. Morimoto¹, K. Hasebe¹, ¹Tokyo Electron Ltd. (Japan), ²Tokyo Electron Yamanashi Ltd. (Japan), ³TEL Technology Center (USA)

PS-1-10

Charge Retention and Stability of Metal Nano Dots in SiO₂; First-principles Study on Metal Dependence

[◦]S. Yamazaki¹, Y. Asayama¹, Y. Onda¹, T. Nakayama¹, ¹Chiba Univ. (Japan)

PS-1-11

Microstructure Analysis of Nanosized Advanced Materials through the ACOM-TEM Technique

[◦]A. Valery^{1,2}, L. Gaben¹, M. Grégoire¹, Y. Le-Friec¹, F. Lorut¹, L. Clément¹, ¹STMicroelectronics (France), ²Univ. Grenoble Alpes, CNRS, SIMAP (France)

PS-1-12(Late News)

Carrier and Heat Transport Properties of Poly-crystalline GeSn on Insulator Substrates

[◦]N. Uchida¹, J. Hattori¹, K. Fukuda¹, T. Maeda¹, R. Lieten^{2,3}, Y. Ohishi¹, R. Takase¹, M. Ishimaru¹, J. Locquet¹, ¹AIST (Japan), ²IMEC (Belgium), ³KU Leuven (Belgium), ⁴Osaka Univ. (Japan), ⁵Kyushu Inst. of Tech. (Japan)

PS-1-13(Late News)

Heavy Sb-doping for Poly-GeSn on Insulator Using Pulsed Laser Annealing in Water

[◦]K. Takahashi^{1,2}, M. Kurosawa^{1,3,4}, H. Ikenoue⁵, M. Sakashita¹, O. Nakatsuka¹, S. Zaima^{1,3}, ¹Grad. Sch. of Engineering, Nagoya Univ. (Japan), ²Research Fellow of JSPS (Japan), ³IMaSS, Nagoya Univ. (Japan), ⁴JST-PRESTO (Japan), ⁵Kyushu Univ. (Japan)

PS-1-14(Late News)

Schottky-barrier-height Reduction for n-Si and n-Ge by Insertion of Tungsten Silicide and Germanide Films Chemically Synthesized using Gas-phase Reactions

[◦]N. Okada^{1,2}, N. Uchida², T. Kanayama², ¹JST-PRESTO (Japan), ²AIST (Japan)

02: Interconnect Technologies and 3D Integration / Sensor / MEMS Intergration / Materials and Characterization

(12 papers)

PS-2-01

A Novel Noise Analysis Method with Multi-physics Simulation for Capacitive CMOS-MEMS Inertial Sensor System

[◦]T. Konishi¹, D. Yamane², H. Ito², S. Doshō², N. Ishihara², H. Toshiyoshi², K. Masu², K. Machida¹, ¹NTT Advanced Tech. Corp. (Japan), ²Tokyo Tech (Japan), ³Univ. of Tokyo (Japan)

PS-2-02

Development of Single Crystalline 4H-SiC MEMS for Harsh Environments

[◦]F. Zhao¹, C. Fang Huang², ¹Washington State Univ. (USA), ²National Tsing Hua Univ. (Taiwan)

PS-2-03

Design and Characterization of the Disk-shaped Piezoresistive Pressure Sensor

[◦]A.Y. Chang¹, S.H. Tseng¹, H.H. Tsai¹, Y.Z. Juang¹, ¹National Applied Research Labs. (Taiwan)

PS-2-04

Reductive Kinetic Study of Oxidized Cu Surface by Catalyzed Formic Acid Vapor

[◦]P.W. Chou¹, [◦]J.M. Song¹, M. Akaike², M. Fujino², T. Suga², J.Y. Lin³, ¹National Chung Hsing Univ. (Taiwan), ²Univ. of Tokyo (Japan), ³Indus. Tech. Res. Inst. (Taiwan)

PS-2-05

High Efficiency MOSFET Bridge Rectifier for AlN MEMS Cantilever Vibration Energy Harvester

[◦]R. Takei¹, H. Okada¹, D. Noda², R. Ohta², T. Takeshita¹, T. Itoh³, T. Kobayashi¹, ¹AIST (Japan), ²Micromachine Center (Japan), ³Univ. of Tokyo (Japan)

PS-2-06

Poly-InSb nMOSFETs for Monolithic 3DIC

[◦]M. Takahashi^{1,2}, T. Irisawa², W.H. Chang², J. Tominaga², S. Fujikawa¹, H. Fujishiro¹, T. Maeda^{1,2}, ¹Tokyo Univ. of Science (Japan), ²AIST (Japan)

PS-2-07

Rotation Analysis of the Light Scattering Variation of Latent Flaws through Light Scattering Measurement with Applied Stress Effect

[◦]Y. Sakata¹, N. Terasaki¹, K. Sakai¹, K. Nonaka¹, ¹AIST (Japan)

PS-2-08

Soft-rubber-packaged PZT MEMS Touch Sensor Optimized for Human-machine Interface Applications

[◦]T. Takeshita¹, T. Kobayashi¹, R. Takei¹, T. Itoh², S. Takamatsu², ¹AIST (Japan), ²Univ. of Tokyo (Japan)

PS-2-09

Physical Surface Treatments for Improving Direct Copper Bonding

[◦]P.H. Chiang¹, [◦]S.Y. Liang¹, J.M. Song¹, S.K. Huang², Y.T. Chiu², C.P. Hung², ¹National Chung Hsing Univ. (Taiwan), ²Advanced Semiconductor Engineering Group (Taiwan)

PS-2-10

Highly Efficient Fiber Coupling Structure for Si Wire Waveguide Using Standard CMOS Compatible SiN Waveguides

[◦]Y. Maegami¹, M. Okano¹, G. Cong¹, M. Ohno¹, K. Yamada¹, ¹AIST (Japan)

PS-2-11

Effect of Plasma Power on Properties of Amorphous Silicon Carbide Hard Mask Films Deposited by Plasma Enhanced Chemical Vapor Deposition

[◦]S. Lee¹, J. Yang¹, D. Lee¹, K. Park¹, G. Hur¹, J. Lee¹, C. Youn², T. Choi¹, ¹TES Co., Ltd (Korea), ²Sejong Univ. (Korea)

PS-2-12(Late News)

Width Dependence of Platinum and Titanium Thermistor Characteristics for Application in Room-Temperature Antenna-Coupled Terahertz Microbolometer

[◦]A. Banerjee¹, H. Satoh¹, A. Tiwari¹, C. Apriono², E.T. Rahardjo², N. Hiromoto¹, H. Inokawa¹, ¹Shizuoka Univ. (Japan), ²Univ. Indonesia (Indonesia)

03: CMOS Devices / Device Physics

(13 papers)

PS-3-01

Accurate Design of Si-Compatible Tunneling Field-Effect Transistor with GeSn Source Junction by *Ab Initio* Calculation and Device Simulation

[◦]J. Lee¹, Y. Cho¹, S. Cho¹, ¹Gachon Univ. (Korea)

PS-3-02

Perspective Analysis of tri-Gate Germanium Tunneling Field Effect Transistor with Dopant Segregation Region at Source/Drain

[◦]L. Liu¹, L. Sun¹, Y. Zhang¹, ¹Peking Univ. (China)

PS-3-03

Influence of Line-Edge Roughness (LER) on Multiple-Gate (MG) Tunnel Field-Effect Transistors (TFETs)

[◦]W.Y. Choi¹, S.H. Choi¹, J.W. Lee¹, I. Huh¹, ¹Sogang Univ. (Korea)

PS-3-04

Investigation of Ge Channel Negative Capacitance FET with Analytical Model: Impact of Ferroelectric Dielectrics

[◦]Y. Peng¹, G. Han¹, Z. Chen¹, Q. Li¹, C. Zhang¹, J. Zhang¹, Y. Hao¹, ¹Xidian Univ. (China)

PS-3-05

Performance Comparison of Si, In_{0.53}Ga_{0.47}As and GaSb 10-nm Double Gate nMOSFETs by Deterministically Solving Time Dependent BTE

[◦]S. Di¹, L. Shen¹, Z. Lun¹, P. Chang¹, K. Zhao^{1,2}, T. Lu¹, G. Du¹, X. Liu¹, ¹Peking Univ. (China), ²Beijing Info. Sci. and Tech. Univ. (China)

PS-3-06

Temperature and Doping Concentration Dependence Characteristics in Junctionless Gate-all-Around Polycrystalline Silicon Thin-Film-Transistors

[◦]C.T. Tso¹, T.Y. Liu¹, F.M. Pan¹, J.T. Sheu¹, ¹NCTU (Taiwan)

PS-3-07

A Physical Based Model for Negative Bias Temperature Instability

[◦]C. Ma¹, [◦]F. Sun¹, L. Zhang², X. Lin¹, M. Chan², ¹Peking Univ. (China), ²Hong Kong Univ. of Sci. and Tech. (Hong Kong)

PS-3-08

Negative Bias Temperature Instability by Body Bias on Ring Oscillators in Thin BOX Fully-Depleted Silicon on Insulator Process

[◦]R. Kishida¹, K. Kobayashi¹, ¹Kyoto Inst. of Tech. (Japan)

PS-3-09

Study of Self-heating Effects in Hybrid SOI/bulk Nanoscale FinFETs

[◦]U. Kumar¹, V. Rao², ¹Indian Inst. of Tech. Bombay (India), ²Indian Inst. of Tech. Delhi (India)

PS-3-10

Analysis and Modeling of Zero- V_{TH} Native Devices with Industry Standard BSIM6 Model

[◦]C. Gupta¹, H. Agarwal¹, Y.K. Lin², S. Khandebla¹, A. Ito³, C. Hrf², Y.S. Chauhan¹, ¹Indian Inst. of Tech. Kanpur (India), ²Univ. of California, Berkeley (USA), ³Broadcom (USA)

PS-3-11

Low Frequency Noise of Accumulation-Mode n- and p-MOSFETs fabricated on (110) Crystallographic Silicon-Oriented Wafers

[◦]P. Gaubert¹, A. Teramoto¹, S. Sugawa¹, ¹Tohoku Univ. (Japan)

PS-3-12

Study on ON-Resistance Degradation Modeling Used for HCI Induced Degradation Characteristic of LDMOS Transistors

[◦]M. Higashino¹, H. Aoki¹, N. Tsukiji¹, M. Kazumi¹, T. Totsuka¹, S. Shibuya¹, K. Kurihara¹, H. Kobayashi¹, ¹Gunma Univ. (Japan)

PS-3-13(Late News)

Multilayer TiNi Alloys as Gate Metal for InGaAs MOS Devices

[◦]H. Do¹, Q. Luc¹, M.Huu Ha¹, S. Huynh¹, C. Chang¹, J. Lin¹, [◦]K. Yang¹, C. FanChang¹, Y. Lin¹, E. Chang¹, ¹NCTU (Taiwan)

04: Advanced Memory Technology

(10 papers)

PS-4-01

Enhanced Operation Characteristics in Poly-Si Nanowire Charge-Trapping Flash Memory Device with Ge Buried Channel

[◦]C. Cheng¹, K.S. Chang-Liao¹, H. Fang¹, C. Huang¹, ¹National Tsing Hua Univ. (Taiwan)

PS-4-02

Modified Switching Mechanism for GeSbTe based Chalcogenide Superlattice Phase Change Memories

[◦]X. Yu¹, [◦]J. Robertson¹, ¹Cambridge Univ. (UK)

PS-4-03

Ab-initio modeling of Conductive channel in Cu – Al₂O₃ conductive bridge RRAM

[◦]J. Dawson¹, [◦]J. Robertson¹, ¹Cambridge Univ. (UK)

PS-4-04

Elliptical Pillar Duplication by Self-Aligned Double Patterning Technology

[◦]A.J. Hong¹, J. Shim¹, M. Lee¹, K. Lee¹, K. Jung¹, J. Hong¹, H. Seong¹, K. Kim¹, S. Jeon¹, Y. Kim¹, J. Park¹, H. Hong¹, K. Lee¹, E. Jung¹, ¹Samsung Electronics Co. Ltd (Korea)

PS-4-05

Compact Model of FeFET Memory Based on Multi-Domain Landau-Khalatnikov Theory

[◦]H. Asai¹, K. Fukuda¹, J. Hattori¹, H. Koike¹, N. Miyata¹, M. Takahashi¹, S. Sakai¹, ¹AIST (Japan)

PS-4-06

SiCOH Low-k material based RRAM for BEOL Process Compatible Nonvolatile Memory Application

[◦]L. Zheng¹, Y. Dai¹, L. Yu¹, L. Chen¹, Q. Sun¹, S. Ding¹, W. Zhang¹, ¹Fudan Univ. (China)

PS-4-07

Enhanced Retention Characteristics in Double Gate Tunnel FET based DRAM

[◦]N. Navlakha¹, J.T. Lin², A. Kranti¹, ¹Indian Inst. of Tech. Indore (India), ²National Sun Yat-Sen Univ. (Taiwan)

PS-4-08

Facile Aqueous Synthesis of CeO₂ Octahedrons for Memristor Application

[◦]H. Du¹, B. Qu¹, T. Wan¹, J. Chen², D. Chu¹, ¹UNSW (Australia), ²IMR, Tohoku Univ. (Japan)

PS-4-09(Late News)

Improvement of Switching Endurance of Conducting-Bridge Random Access Memory by Addition of Metal Ion-Containing Ionic Liquid

[◦]K. Kinoshita¹, A. Harada¹, H. Yamaoka¹, A. Sakaguchi¹, K. Watanabe¹, S. Kishida¹, Y. Fukaya¹, T. Nokami¹, T. Itoh¹, ¹Tottori Univ. (Japan)

PS-4-10(Late News)

One-Transistor Ferroelectric Versatile Memory with Multi-Level Operation

[◦]Y.C. Chiu¹, [◦]Y.W. Hung¹, C.C. Fan¹, C. Liu¹, W.W. Lai¹, Y.R. Chen¹, P.W. Chen¹, C.H. Cheng¹, C.Y. Chang¹, W.C. Chou¹, ¹NCTU (Taiwan), ²National Taiwan Normal Univ. (Taiwan)

05: Advanced Circuits and Systems

(8 papers)

PS-5-01

Novel Integrated Voltage Regulators with High-Side NMOS Power Switch and Dedicated Bootstrap Driver Using Vertical MOSFET for Efficiency Enhancement

[◦]K. Itoh^{1,2,3}, M. Muraguchi^{1,2,3}, T. Endoh^{1,2,3}, ¹Graduate School of Eng., Tohoku Univ. (Japan), ²CIES, Tohoku Univ. (Japan), ³JST-ACCEL (Japan)

PS-5-02

Temperature Sensor Using Cascoded Diode-connected MOSFETs Operating in Sub-threshold Region

[◦]R.L. Wang¹, J.L. Shi¹, Y.F. Hao¹, [◦]C.S. Tsai¹, L.W. Wang¹, K.B. Lee¹, Y.T. Chuang², H.H. Liao², H.H. Tsai², Y.Z. Juang², ¹National Kaohsiung Normal Univ. (Taiwan), ²National Applied Research Labs. (Taiwan)

PS-5-03

Multi-Ring MOSFETs for Mobility Enhancement and Parasitic Resistances Reduction in RF and Analog Applications

[◦]Y.Y. Lin¹, [◦]J.C. Guo¹, ¹NCTU (Taiwan)

PS-5-04

Noise Analysis of a Serial Multiple Sampling in Back-Illuminated CMOS Image Sensor

[◦]H. Wakabayashi¹, K. Yamaguchi¹, Y. Yamagata², ¹Sony Semiconductor Solutions Corp. (Japan), ²Sony LSI Design Inc. (Japan)

PS-5-05

A Gain Cell Array with Retention Increment Design for Bit-Area Efficient On-Chip Memory Applications

[◦]S. Manisankar¹, H. Kim¹, Y. Chung¹, ¹Kyungpook National Univ. (Korea)

PS-5-06

An All-Digital Duty-Cycle Corrector with Synchronous and High Accuracy Output for DDR-SDRAM Application

[◦]Y.L. Lo¹, [◦]C.W. Tsai², C.C. Chang¹, H.Y. Liu¹, W.B. Yang², K.H. Cheng², ¹National Kaohsiung Normal Univ. (Taiwan), ²National Central Univ. (Taiwan), ³Tamkang Univ. (Taiwan)

PS-5-07

Property-Driven Functional Verification Technique for High-Speed Vision System-on-Chip Processor

[◦]V. Nshunguyimfura¹, J. Yang¹, L. Liu¹, N. Wu¹, ¹Chinese Academy of Sciences (China)

PS-5-08(Late News)

Analysis and Suppression of Low-Frequency Noise for Two-Dimensional Integrated Magnetic Sensor

[◦]T. Kimura¹, Y. Sakairi¹, A. Mori¹, T. Masuzawa¹, ¹Ibaraki Univ. (Japan)

06: Compound Semiconductor Electron Devices & Related Technologies

(14 papers)

PS-6-01

InAs Quantum-Well MOSFET Performance Improvement by Using PEALD AlN Passivation Layer and *In-Situ* NH₃ Post Remote-Plasma Treatment

[◦]P.C. Chang¹, Q.H. Luc¹, G.Y. Lin¹, [◦]C.C. Chang¹, J.W. Lin¹, C.C. Fan Chang¹, K.S. Yang¹, Y.C. Lin¹, S.M. Sze¹, E.Y. Chang¹, ¹NCTU (Taiwan)

PS-6-02

Deposition Temperature and Al₂O₃ Thickness Dependence on the Mobility of HfO₂/Al₂O₃/InGaAs Gate Stacks

[◦]K. Ohsawa¹, N. Kise¹, Y. Miyamoto¹, ¹Tokyo Tech (Japan)

PS-6-03

Equivalent Oxide Thickness Self-Reduction and Work Function Self-Alignment Using Ti/AlN Doping Layer for Mo/HfO₂/InGaAs NMOS

[◦]H. Do¹, Q. Luc¹, M. Ha¹, S. Huynh¹, C. Chang¹, J. Lin¹, K. Yang¹, C. Chang¹, Y. Lin¹, E. Chang¹, ¹NCTU (Taiwan)

PS-6-04

Effect of Interface Traps on the Device Performances of the Tunneling Field-Effect Transistors Based on InGaAs

[◦]R.H. Kwon¹, Y.J. Yoon¹, J.H. Seo¹, Y.I. Jang¹, M.S. Jo¹, J.-H. Lee¹, I.M. Kang¹, ¹Kyungpook National Univ. (Korea)

PS-6-05

Atomic-Layer Deposited High-k Metal Gates of Ge/III Metal -Oxide-Semiconductor Devices and numerical simulations

[◦]B.Y. Chen^{1,2}, [◦]C.L. Chu¹, J.L. Chen³, G.L. Luo⁴, T.T. Li⁴, E.Y. Chang², ¹National Nano Device Labs. (Taiwan), ²NCTU (Taiwan), ³I-Shou Univ. (Taiwan), ⁴National Central Univ. (Taiwan)

PS-6-06

The Study of GaN-based Fin-HEMT with Low Current Collapse Phenomenon by Plasma Enhanced Atomic Layer Deposition

[◦]A. Tzou¹, S. Chen¹, Z. Li², C. Chang¹, H. Kuo^{1,2}, ¹NCTU (Taiwan), ²National Nano Device Labs. (Taiwan), ³Epistar (Taiwan)

PS-6-07

Effects of Different Fe-doped GaN Buffer in AlGaIn/GaN HEMTs on Si Substrate

[◦]S.C. Chen¹, J.W. Chiu¹, B.H. Li¹, H.C. Chiu¹, R. Xuan², C.W. Hu², ¹Chang Gung Univ. (Taiwan), ²Episil-Precision Inc (Taiwan)

PS-6-08

Leakage Current Reduction of Gated Ohmic Anode AlGaIn/GaN Schottky Barrier Diode by Applying Anode Edge Termination

[◦]R. Ki¹, I. Hwang¹, H. Cha², K. Seo¹, ¹Seoul National Univ. (Korea), ²Hongik Univ. (Korea)

PS-6-09

The Influence of AlGaN/GaN Schottky Barrier Diode (SBD) with SiH₄ Doping in Barrier Layer
°J.W. Chiu¹, S.C. Chen¹, B.H. Li¹, H.C. Chiu¹, R. Xuan², C.W. Hu², ¹Chang Gung Univ. (Taiwan),
²Episil-Precision Inc (Taiwan)

PS-6-10

ZnO and ZnON Film-Profile Engineered TFTs for BEOL High-Voltage Operations
°M. Wu¹, H. Lin¹, P. Li¹, T. Huang¹, ¹NCTU (Taiwan)

PS-6-11

High-Performance Thin-Film Transistors with ZnO/Al₂O₃ Superlattice Channel by Atomic Layer Deposition
°G.D. Cui¹, D.D. Han¹, J.C. Dong¹, Y.Y. Cong¹, X.M. Zhang¹, H.J. Li¹, W. Yu¹, S.D. Zhang¹, X. Zhang¹, Y. Wang¹, ¹Peking Univ. (China)

PS-6-12

Room-temperature Fabrication of Amorphous IGZO TFTs with Co-sputtered Zr_xSi_{1-x}O₂ Gate Dielectrics
P.Y. Liu¹, S.J. Wang¹, C.H. Hung¹, C.H. Wu², N.S. Wu¹, °H.P. Yan¹, T.H. Lin¹, ¹National Cheng Kung Univ. (Taiwan), ²Chung Hua Univ. (Taiwan)

PS-6-13

Study of Fabrication and Current-voltage Characteristics of MoS₂/WSe₂ Heterojunction Diode
°Y.H. Jiang¹, ¹National Taiwan Univ. of Sci. and Tech. (Taiwan)

PS-6-14(Late News)

Hydrazine (N₂H₄)-based Surface Treatment Method for AlGaIn/GaN MIS-HEMTs with a High Quality Interface
°H. Jung¹, M. Shin¹, H. Ahn¹, J. Do¹, S. Chang¹, K. Cho¹, B. Min¹, H. Kim¹, H. Yoon¹, J. Lim¹,
¹Electronics and Telecommunications Res. Inst. (Korea)

07: Photonic Devices and Related Technologies

(13 papers)

PS-7-01

Low Threshold Current AlGaAsSb/InGaAsSb/GaSb Quantum Well Laser Operating at Wavelength of 2-µm
X. Li¹, °H. Wang¹, Z.L. Qiao¹, C.Y. Liu¹, ¹Nanyang Technological Univ. (Singapore)

PS-7-02

Experimental Observation of Direct Bandgap Photoluminescence from Tensile-strained Ge Nanodots Embedded within SiO₂ Matrix
°M.H. Kuo¹, S.K. Chou¹, W.T. La², Y.W. Pan², S.D. Lin², T. George², P.W. Li^{1,2}, ¹National Central Univ. (Taiwan), ²NCTU (Taiwan)

PS-7-03

Passivation Effect of Ozone Water Treatment of InGaN/GaN Nanostructures Fabricated by Hydrogen Environment Anisotropic Thermal Etching (HEATE)
°K. Ogawa¹, T. Mizutani¹, S. Ishijima¹, Y. Namae¹, A. Matsuoka¹, A. Kikuchi^{1,2}, ¹Sophia Univ. (Japan),
²Sophia Nanotech. Res. Center (Japan)

PS-7-04

Withdrawn

PS-7-05

High Sensitivity Flexible Metal-Insulator-Metal Localized Surface Plasmon Resonance Sensors on PDMS Substrate
°H.T. Lin^{1,2}, C.Y. Chang¹, S.W. Huang¹, T.Y. Shieh^{1,2}, M.H. Shih^{1,2,3}, ¹Academia Sinica (Taiwan),
²NCTU (Taiwan), ³National Sun Yat-sen Univ. (Taiwan)

PS-7-06

Fabrication of Surface Plasmon Resonance Sensors with Highly Uniform Metallo-Dielectric Nanostructures over a Large Area
°J.F. Luo¹, N.T. Huang¹, C.L. Wu¹, L.A. Wang¹, ¹National Taiwan Univ. (Taiwan)

PS-7-07

Plasmonic Hole Array Perfect Absorbers for Wavelength-Selective Infrared Pyroelectric Detectors
°T. Dao^{1,2}, S. Ishii^{1,2}, T. Yokoyama^{1,2}, T. Sawada^{1,2}, R. Sugavaneshwar^{1,2}, K. Chen^{1,2}, Y. Wada¹, T. Nabatame^{1,2}, T. Nagao^{1,2,3}, ¹NIMS (Japan), ²JST-CREST (Japan), ³Hokkaido Univ. (Japan)

PS-7-08

GaN Metal-Organic-Metal Ultraviolet Sensors with Fullerene Organic Layers
°C.-H. Chen¹, M.-H. Yang¹, ¹Cheng Shiu Univ. (Taiwan)

PS-7-09

A New Method of Fabricating Fabry-Pérot Type Optical Fiber Temperature Sensor using an External Silicon Microsphere
°S.S. Chang¹, J.H. Chen¹, G.H. Chen¹, L.A. Wang¹, ¹National Taiwan Univ. (Taiwan)

PS-7-10

Si Slot Waveguide with Er₂Y_{2-x}SiO₅ Coupled with Si Wire and Distributed Bragg Reflector
°Y. Tsuyuki¹, G. Nakamura¹, H. Isshiki¹, ¹The Univ. of Electro-Communications (Japan)

PS-7-11

Numerical Analysis of InGaAsP Carrier-depletion Optical Modulator on III-V CMOS Photonics Platform
°N. Sekine¹, J. Han^{1,2}, M. Takenaka^{1,2}, S. Takagi^{1,2}, ¹Univ. of Tokyo (Japan), ²JST-CREST (Japan)

PS-7-12

Wavelength Dependent Photodetection Characteristics of Avalanche Photodiode Fabricated by Standard CMOS Process
°Z.A.F.M. Napiah^{1,2}, T. Hishiki¹, K. Iiyama¹, ¹Kanazawa Univ. (Japan), ²UTeM (Malaysia)

PS-7-13

Highly Stable Electro-Optic Polymers for TiO₂ Vertical Slot Waveguide Modulators and Efficiently Poling
°Y. Enami¹, ¹Kochi Univ. of Tech. (Japan)

08: Advanced Material Synthesis and Crystal Growth Technology

(12 papers)

PS-8-01

Etch-pit and Grown-in Dislocations in CVD Homoepitaxial Diamond
°N. Tsubouchi¹, Y. Mokuno¹, ¹AIST (Japan)

PS-8-02

Ni-induced Layer Exchange Crystallization of Sputtered Amorphous Carbon for Multi-layer Graphene on Insulator
°H. Murata¹, K. Toko¹, T. Suemasu¹, ¹Univ. of Tsukuba (Japan)

PS-8-03

Synthesis of Si Nanosheet Bundles by Extraction of Ca Atoms from CaSi₂ Powders by Inositol Hexakisphosphate Solution
°X. Meng¹, K. Sasaki¹, Y. Kumazawa¹, P. Yuan¹, H. Tatsuoka¹, ¹Shizuoka Univ. (Japan)

PS-8-04

Reliability of Epitaxial Nickel Disilicide Thin Film
°C. Hsin¹, S. Lee¹, ¹National Central Univ. (Taiwan)

PS-8-05

Influence of Post Annealing Treatment on Fixed Charge State and Chemical Bonding State of Sr-silicate Film
°S. Taniwaki¹, M. Umano¹, H. Yoshida¹, K. Arafune¹, S. Satoh¹, Y. Hotta¹, ¹Univ. of Hyogo (Japan)

PS-8-06

Formation of AlO_x/GeO_x/Ge Gate Stack Structure by Thermal Oxidation
°A. Heya¹, N. Matsu¹, ¹Univ. of Hyogo (Japan)

PS-8-07

Fabricating High Quality YIG Thin Film by Mist CVD under Open-Air Atmospheric Pressure
°L. Liu¹, Y. Siwa¹, Y. Nakasone¹, M. Nishi¹, E.K.C. Pradeep¹, T. Kawaharamura¹, ¹Kochi Univ. of Tech. (Japan)

PS-8-08

Bismuth Doping Effect on Structural and Photocatalytic Activity of Bi-doped TiO₂ Nanoparticles
°Y.-H. Chang¹, K.-C. Hsiao¹, T.-H. Lin¹, P.-Y. Wu¹, Y.-K. Tseng¹, T.-F. Lin¹, M.-C. Wu^{1,2}, ¹Chang Gung Univ. (Taiwan), ²Chang Gung Memorial Hospital (Taiwan)

PS-8-09

The Properties of the In_xGa_{1-x}Sb Epilayer Grown on GaAs Substrate by Metalorganic Chemical Vapor Deposition Using the Interfacial Misfit Dislocation Technique
°S. Huynh¹, Q. Luc¹, M. Ha¹, H. Do¹, H. Yu¹, E. Chang¹, ¹NCTU (Taiwan)

PS-8-10

The Growth of In_xGa_{1-x}Sb Epilayer on GaAs Substrate by Metalorganic Chemical Vapor Deposition Using an Interfacial Misfit Dislocation GaSb Buffer Layer
S. Huynh¹, M. Ha¹, Q. Luc¹, H. Do¹, C. Hsiao², C. Chang¹, °J. Lin¹, H. Yu¹, E. Chang¹, ¹NCTU (Taiwan), ²National Cheng Kung Univ. (Taiwan)

PS-8-11(Late News)

Preparation of IGZO Thin Layer by a Low-temperature Non-vacuum Technique
°E.K.C. Pradeep¹, G.T. Dang¹, M. Ohtani¹, K. Kobiro¹, T. Kawaharamura¹, ¹Kochi Univ. of Tech. (Japan)

PS-8-12(Late News)

Crystallographic Polarity Effect of ZnO on Thin Film Growth of Pentacene
T. Nakamura^{1,2}, °T. Nagata¹, R. Hayakawa¹, T. Yoshimura², S. Oh¹, N. Hiroshiba^{3,1}, T. Chikyow¹, N. Fujimura², Y. Wakayama¹, ¹NIMS (Japan), ²Osaka Prefecture Univ. (Japan), ³Tohoku Univ. (Japan)

09: Physics and Applications of Novel Functional Devices and Materials

(14 papers)

PS-9-01

Wide-field Imaging of Magnetic Field with Nitrogen-vacancy Centers in Diamond by Frequency Modulation of Microwaves
Y. Miura¹, S. Kashiyawa², °S. Nomura¹, ¹Univ. of Tsukuba (Japan), ²AIST (Japan)

PS-9-02

Low-noise and Wide-bandwidth Current Readout at Low Temperatures Using a Superconducting-quantum-interference-device Amplifier
°M. Tran^{1,2}, Y. Okazaki¹, S. Nakamura¹, M. Ortolan², N. Kaneko¹, ¹AIST (Japan), ²Politecnico di Torino (Italy)

PS-9-03

Transport property of NbSe₂/WSe₂ van der Waals Junction
°Y. Sata¹, R. Moriya¹, Y. Hoshi¹, S. Masubuchi¹, K. Watanabe², T. Taniguchi², K. Ueno³, T. Machida^{1,4}, ¹IIS, Univ. of Tokyo (Japan), ²NIMS (Japan), ³Saitama Univ. (Japan), ⁴INQIE, Univ. of Tokyo (Japan)

PS-9-04

Optical Characterization of Ultrathin Ge-on-Insulator: Electron and Phonon Confinement, Raman Enhancement, Optical Phonon Lifetime Reduction, Acoustic Phonon Spectral Reconstruction and Drop in Thermal Conductivity
°V. Poborchii¹, H. Ishii¹, H. Hattori¹, W. Chang¹, T. Tada¹, P. Geshev², T. Maeda¹, ¹AIST (Japan), ²Institute of Thermophysics (Russia)

PS-9-05

High-performance Si-doped ZnO Thin-film Transistors Fabricated on Flexible Plastic Substrate at Low Temperature

H. Li¹, D. Han¹, *G. Cui¹, W. Yu¹, Y. Cong¹, S. Zhang¹, X. Zhang¹, Y. Wang¹, ¹Peking Univ. (China)

PS-9-06

Resistive Switching in Planar Metal/NiO Bilayer System with Low Voltage Operation

*Y. Nakano¹, K. Okabe¹, T. Kimura¹, ¹Kyushu Univ. (Japan)

PS-9-07

Ultrafine (≤ 10 nm) InGaN Quantum Structures Fabricated by Hydrogen Environment Anisotropic Thermal Etching (HEATE)

*S. Ishijima¹, T. Mizutani¹, K. Ogawa¹, Y. Namee¹, A. Matsuoka¹, A. Kikuchi^{1,2}, ¹Sophia Univ. (Japan), ²Sophia Nanotech. Res. Center (Japan)

PS-9-08

Hole-Tunneling Si_{1-x}Ge_x/Si ASDQW RTD with High Resonant Current and High Peak-to-Valley Current Ratio

*A. Shinkawa¹, M. Wakiya¹, Y. Maeda¹, T. Tsukamoto¹, Y. Suda¹, ¹Tokyo Univ. of Agri. & Tech. (Japan)

PS-9-09

DFT-based *ab initio* MD Simulation of the Ionic Conduction in N/F-Doped ZrO₂ under Epitaxial Strain

*M. Oka¹, H. Kamisaka¹, T. Fukumura², T. Hasegawa^{1,3}, ¹Univ. of Tokyo (Japan), ²Tohoku Univ. (Japan), ³KAIST (Japan)

PS-9-10

Withdrawn

PS-9-11(Late News)

Electronic Band Structure of TiN/MgO nanostructures

*K. Kobayashi¹, H. Takaki^{1,2}, M. Shimonoi¹, N. Kobayashi², K. Hirose³, ¹NIMS (Japan), ²Univ. of Tsukuba (Japan), ³NEC Corp. (Japan)

PS-9-12(Late News)

Gate-stack Engineering of Self-organized Nanospherical Ge-gate/SiO₂/Si_xGe_{1-x}-channel on Si (100) and Si (110) for Ge MOS Devices

P.H. Liao¹, C.W. Tien², K.P. Peng², H.C. Lin², T. George¹, *P.W. Li^{1,2}, ¹National Central Univ. (Taiwan), ²NCTU (Taiwan)

PS-9-13(Late News)

Static and Dynamic Contacts in Graphene Nano-Electro-Mechanical (NEM) Switches

*W. Wang¹, M. Muruganathan¹, H. Mizuta^{1,2}, ¹JAIST (Japan), ²Univ. of Southampton (UK)

PS-9-14(Late News)

Optical Modulating Device using Phase Transition of [(GeTe)₂(Sb₂Te₃)₂]_n Superlattice

*T. Sugiyama¹, A. Kubo¹, T. Nakano², ¹Univ. of Tsukuba (Japan), ²AIST (Japan)

10: Organic Materials Science, Device Physics, Applications and Printed Technologies

(13 papers)

PS-10-01

Nanoimprint TiO₂ Slot Layer for Hybrid EO polymer/TiO₂ Vertical Slot Waveguide Modulators

Y. Jouane¹, *Y. Enami¹, ¹Kochi Univ. of Tech. (Japan)

PS-10-02

Control of Crystalline Nesting Structure of Vacuum Deposited Organic Photovoltaic Cells by Co-evaporant Induced Crystallization Method

*T. Kaji¹, M. Katayama¹, ¹Tokyo Univ. of Agri. & Tech. (Japan)

PS-10-03

Introducing Position Effect of Trifluoromethyl Moiety on Bis-styrylbenzene Skeleton

*H. Mochizuki¹, ¹AIST (Japan)

PS-10-04

Characteristics of Bis-styrylbenzene Derivatives with Various Electron-withdrawing Groups

*H. Mochizuki¹, M. Chikamatsu¹, ¹AIST (Japan)

PS-10-05

Ferroelectric and Piezoelectric Properties of P(VDF-TrFE) Gels

*M. Fukagawa¹, M. Morimoto¹, Y. Koshiba¹, K. Ishida¹, ¹Kobe Univ. (Japan)

PS-10-06

Doping Level Control and Thermoelectric Property of Vapor Phase Polymerization PEDOT thin films

*M. Hirai¹, S. Horike¹, Y. Koshiba¹, M. Morimoto¹, K. Ishida¹, ¹Kobe Univ. (Japan)

PS-10-07

Phase Transition Field-Effect Transistor using α -(BEDT-TTF)₂I₃ Single-Crystal

*Y. Okada¹, T. Ueda¹, D. Yamamoto¹, H. Yamauchi¹, M. Sakai¹, K. Kudo¹, ¹Chiba Univ. (Japan)

PS-10-08

Field Dependence of the Space-charge Limited Current in Polycrystalline Pentacene

*T. Hayashi¹, A. Naka¹, A. Fujiwara¹, T. Yokota^{2,3}, T. Someya^{2,3}, ¹NTT BRL (Japan), ²Univ. of Tokyo (Japan), ³JST-ERATO (Japan)

PS-10-09

Metal-Atom Penetration and Clustering Processes in PTCDA Thin Films; First-Principles Study of Film Degradation

*K. Kawabata¹, T. Nakayama¹, ¹Chiba Univ. (Japan)

PS-10-10

Interface Control between an Electrode and a Hole-Transport Polymer via Self-Assembled Monolayers

S. Ono¹, S. Usui², K. Tanaka¹, *H. Usui¹, ¹Tokyo Univ. of Agri. & Tech. (Japan), ²Niigata Univ. (Japan)

PS-10-11

The Charging-Relaxation of Carriers in High Response Organic Phototransistor with Au Nanoparticles

S.-H. Yuan², *Z. Pei¹, C.-H. Chen³, ¹National Chung Hsing Univ. (Taiwan), ²National Central Univ. (Taiwan), ³Indus. Tech. Res. Inst. (Taiwan)

PS-10-12

Effect of Geometrical Shape of Nozzle Tip on Electro spray Deposition of Organic Thin Film

*H. Ueda¹, K. Takeuchi¹, A. Kikuchi^{1,2}, ¹Sophia Univ. (Japan), ²Sophia Nanotech. Res. Center (Japan)

PS-10-13

Molecular Dynamics Simulation of Thin Film Growth of Organic Semiconductors

*T. Shimada¹, T. Tamura¹, T. Nagahama¹, T. Yanase¹, ¹Hokkaido Univ. (Japan)

11: Sensors and Materials for Biology, Chemistry and Medicine

(9 papers)

PS-11-01

A High Sensitivity Gas Sensor for Nitric Oxide: Poly-Si Nanowire FETs with Phthalocyanine Complexes Surface Modification

*P.Y. Chuang¹, H.M. Chen¹, ¹NCTU (Taiwan)

PS-11-02

Copper Phthalocyanine and Hexadecafluorophthalocyanine Enhancing Nitric Oxide Gas Sensitivity of p-Si NWs FETs

*T.Y. Cheng¹, H.M. Chen¹, ¹NCTU (Taiwan)

PS-11-03

Effect of Chemical Surface Modification on Cell/Graphene Gate Transistor

*N. Nishi¹, K. Nishimura¹, K. Tsushima¹, M. Sota¹, X. Chen¹, T. Murakami¹, Y. Miyazawa², T. Kajisa², M. Kato¹, R. Komatani¹, S. Chiashi¹, S. Maruyama¹, T. Sakata¹, ¹Univ. of Tokyo (Japan), ²PROVIGATE Inc. (Japan)

PS-11-04

Concentration Effect of Graphene Oxide on Microdomains in Multicomponent Lipid Bilayer Membranes

*Y. Okamoto¹, S. Saito¹, S. Iwasa¹, R. Tero¹, ¹ToyoHashi Univ. of Tech. (Japan)

PS-11-05

Non-Lithographic Au Film over Nanosphere SERS Substrate

A. Purwidyantri¹, *C.S. Lai^{1,2,3}, ¹Chang Gung Univ. (Taiwan), ²Chang Gung Memorial Hospital (Taiwan), ³Ming Chi Univ. of Tech. (Taiwan)

PS-11-06(Late News)

A Highly Selective Hydrogen Sensor Based on Self-heated Polysilicon Nanobelt Device

*N.A. Tran¹, F.M. Pan¹, J.T. Sheu¹, ¹NCTU (Taiwan)

PS-11-07(Late News)

Diagnosis of Immediate-type Allergy using SPR Imaging Sensor

*Y. Yanase¹, T. Kawaguchi¹, K. Sakamoto², M. Hide¹, ¹Hiroshima Univ. (Japan), ²Kyushu Inst. of Tech. (Japan)

PS-11-08(Late News)

A Rapid Biosensing Platform Utilizing Si Nanowire Photovoltaic Array and Immunogold Silver Staining

*C.-W. Chen¹, Y.-M. Wu¹, W.-C. Lee², T.-Y. Liu¹, F.-M. Pan¹, J.-T. Sheu¹, ¹NCTU (Taiwan)

PS-11-09(Late News)

Size Effects of Pt Nanoparticle/Graphene Composite Materials on the Electrochemical Sensing of Hydrogen Peroxide and Glucose

*H.C. Hsu¹, J.A. Pai¹, Y.H. Lin¹, J.S. Su¹, C.L. Sun^{1,2}, ¹Chang Gung Univ. (Taiwan), ²Chang Gung Memorial Hospital (Taiwan)

12: Spintronics Materials and Devices

(20 papers)

PS-12-01

Gate Controlled Switching between Two Different Persistent Spin Helix States and Determination of Dresselhaus Spin-orbit Interaction Parameter

K. Yoshizumi¹, M. Kohda¹, *J. Nitta¹, ¹Tohoku Univ. (Japan)

PS-12-02

A Self-Terminated Energy-Efficient Nonvolatile Flip-Flop Using 3-terminal Magnetic Tunnel Junction Device

*D. Suzuki¹, T. Hanyu¹, ¹Tohoku Univ. (Japan)

PS-12-03

Spin-valve Effect in Nanoscale Si-based Devices with Ferromagnetic Electrodes

*D.H. Duong¹, M. Tanaka², N.H. Pham^{1,2}, ¹Tokyo Tech (Japan), ²Univ. of Tokyo (Japan)

PS-12-04

Improvement of Brillouin Light Scattering Signal by using Anti-reflection Coating Layer for Magnetic Multilayers

*J. Jung¹, N.H. Kim¹, K. Park¹, H.K. Hwang¹, J.S. Kim¹, C.Y. You¹, ¹DGIST (Korea)

PS-12-05

Integration of Si Nanowire Waveguides and Magneto-optical Plasmonic Waveguides on a Si Substrate

*V. Zayets¹, H. Saito¹, S. Yuasa¹, ¹AIST (Japan)

PS-12-06
Effect of an Mg-Al Insertion for Directly Sputtered MgAl₂O₄ (001)-based Epitaxial Magnetic Tunnel Junctions

°M. Belmoubarik¹, H. Sukegawa¹, S. Mitani¹, K. Hono¹, ¹NIMS (Japan)

PS-12-07
Fabrication of a Spin Injection Device Having a Top-gate Structure

°W. Nomura¹, T. Miyakawa¹, M. Yamamoto¹, T. Uemura¹, ¹Hokkaido Univ. (Japan)

PS-12-08
Spin Hall Effect-based Asynchronous Nanomagnetic Logic Devices

°V.P.K. Miriyala¹, M.B.A. Jalil¹, G. Liang¹, ¹National Univ. of Singapore (Singapore)

PS-12-09
Resistance Drift and Degradation of Fe/Spinel MgAl₂O₄/Fe (001) Magnetic Tunnel Junctions

°C. Choi¹, H. Sukegawa², S. Mitani², Y. Song¹, ¹Hanyang Univ. (Korea), ²NIMS (Japan)

PS-12-10
Modeling and Evaluation of Interface Perpendicular Magnetic Anisotropy in Ta/NiFe/Pt Trilayers

°S. Hirayama^{1,2}, S. Kasai¹, S. Mitani^{1,2}, ¹NIMS (Japan), ²Univ. of Tsukuba (Japan)

PS-12-11
Research on the Failure Cell Screen Method of MgO Based MTJ

°K. Kim¹, C. Choi¹, Y. Oh¹, H. Sukegawa², S. Mitani², Y. Song¹, ¹Hanyang Univ. (Korea), ²NIMS (Japan)

PS-12-12
Fabrication of Bi₂Y₁Fe₃O₁₂ Films on Glass and Silicon Substrates by Metal Organic Decomposition Method for Photonic Integrated Circuits

M. Hosoda¹, J. Sato¹, D.A. Wahid¹, °H. Shimizu¹, ¹Tokyo Univ. of Agri. & Tech. (Japan)

PS-12-13
Influence of Surface Smoothing on Spin Seebeck Effect of Ce₃Y₂Fe₅O₁₂ Deposited by Metal Organic Decomposition

°S. Hirata¹, T. Ono¹, Y. Amemiya¹, T. Tabei¹, S. Yokoyama¹, ¹Hiroshima Univ. (Japan)

PS-12-14
Effect of Post-annealing on Magnetic Properties of Ternary Transition-metal Chalcogenide (Cr,Fe)_{1-x}Te thin films grown by MBE

°H. Tsuruoka¹, K. Kanazawa¹, S. Kuroda¹, ¹Univ. of Tsukuba (Japan)

PS-12-15
Magnetic Phase Diagram and Effect of Capping Layer on Ferromagnetism in High T_c Ferromagnetic Oxide Semiconductor Anatase Co-doped TiO₂

T.K. Krastienapibal¹, Y. Koshimoto², D. Oka², °T. Fukumura², T. Hasegawa¹, ¹Univ. of Tokyo (Japan), ²Tohoku Univ. (Japan)

PS-12-16
Stochastic Macro-model of Magnetic Tunnel Junction for Spice Simulation about Writing Current Density Dependence on Resistance Variation

°J. Choi¹, H. Sukegawa², S. Mitani², Y. Song¹, ¹Hanyang Univ. (Korea), ²NIMS (Japan)

PS-12-17(Late News)
Epitaxial Growth of Bi₂Te₃ Topological Insulator Thin Films with Persistent Linear Magnetoresistance Behaviors

H.Y. Lee¹, Y.S. Chen¹, Y.C. Lin¹, °Y.C. Lee¹, C.T. Liang¹, Y.H. Chang¹, ¹National Taiwan Univ. (Taiwan)

PS-12-18(Late News)
Epitaxial Growth and Magnetic Properties of Fe₃O₄ Film on Si (111) Substrate

°N. Takahashi¹, Y. Yamamoto¹, T. Yanase¹, T. Shimada¹, T. Nagahama¹, ¹Hokkaido Univ. (Japan)

PS-12-19(Late News)
Fabrication of Tunnel Junctions with Fe₃O₄ Electrode and MgO Barrier

°Y. Yamamoto¹, S. Sasaki¹, T. Yanase¹, T. Shimada¹, T. Nagahama¹, ¹Hokkaido Univ. (Japan)

PS-12-20(Late News)
Minority Spin Transport in Epitaxially Grown Nickel-Iron Nitride Films

°F. Takata¹, K. Ito^{1,2,3}, K. Kabara², S. Higashikozono¹, T. Gushi¹, K. Toko¹, M. Tsunoda², T. Suemasa¹, ¹Univ. of Tsukuba (Japan), ²Tohoku Univ. (Japan), ³JSPS (Japan)

13: Applications of Nanotubes, Nanowires, and Graphene and related 2D materials (15 papers)

PS-13-01
Thickness-Dependent Flatband Voltage Shift in MOSCAP with MoS₂ and High-*k* Gate Dielectric

°R. Yang¹, J. Cai², S. Wang², D. Chi², K.W. Ang¹, ¹National Univ. of Singapore (Singapore), ²Institute of Materials Research and Engineering (Singapore)

PS-13-02
First Principles Calculation of Charged Vacancies in Single-Layer Molybdenum Disulfide

°S. Urasaki¹, H. Kageshima¹, ¹Shimane Univ. (Japan)

PS-13-03
High Performance Ultrathin Micro-Supercapacitors

°F. Tanaka¹, A. Sekiguchi², K.U. Laszczyk¹, K. Kobashi², T. Yamada², K. Hata², ¹TASC (Japan), ²AIST (Japan)

PS-13-04
High-Mobility and Low-Carrier-Density Sputtered-MoS₂ Film by Low-Temperature Forming-Gas Annealing for 3D-IC

°J. Shimizu¹, T. Ohashi¹, K. Matsuura¹, I. Muneta¹, K. Kakushima¹, K. Tsutsui¹, H. Wakabayashi¹, ¹Tokyo Tech (Japan)

PS-13-05
Combination of Synthesis and Post-synthesis Approaches for the Preparation of Single-Walled Carbon Nanotubes with a High Percentage of Semiconductor-type

°S. Sakurai¹, S. Li^{1,3}, M. Yamada¹, H. Sakurai^{1,2}, A. Sekiguchi¹, F. Tanaka^{1,2}, D. Futaba¹, K. Hata¹, ¹AIST (Japan), ²TASC (Japan), ³National Univ. of Singapore (Singapore)

PS-13-06
Centimeter-scale High-performance Few-layer MoS₂ Fabricated by RF Magnetron Sputtering and Subsequent Post-deposition Annealing

°S. Ishihara^{1,3}, Y. Hibino¹, N. Sawamoto¹, T. Ohashi², K. Matsuura², H. Wakabayashi², A. Ogura¹, ¹Meiji Univ. (Japan), ²Tokyo Tech (Japan), ³Research Fellow of JSPS (Japan)

PS-13-07
Thin Film Transistors with Length-sorted Single-wall Carbon Nanotubes

°Y. Kuwahara¹, F. Nihey², T. Saito¹, ¹AIST (Japan), ²NEC Corp. (Japan)

PS-13-08
Growth of Graphene/3C-SiC (111)/4H-SiC (0001) by a Sublimation Technique with a Vertical Infrared-Lamp Annealer

°Y. Sekine¹, K. Kumakura¹, H. Hibino^{1,2}, ¹NTT BRL (Japan), ²Kwansei Gakuin Univ. (Japan)

PS-13-09
Effects of Nickel Doping on the Optical and Electrical Properties of MoS₂ Photodetectors

°Z.W. Chen¹, T.S. Ko¹, D.Y. Lin¹, J. Suh², Z.S. Chen¹, ¹National Changhua Univ. of Edu. (Taiwan), ²Cornell Univ. (USA)

PS-13-10
Fabrication of Graphene/Diamond Heterojunctions and Their Electronic Properties

°K. Ueda¹, S. Tanaka¹, H. Asano¹, ¹Nagoya Univ. (Japan)

PS-13-11
Structural and Optical Properties of Wurtzite InP/AlInP Core-Multishell Nanowires

°F. Ishizaka¹, Y. Hiraya¹, K. Tomioka^{1,2}, J. Motohisa¹, T. Fukui¹, ¹Hokkaido Univ. (Japan), ²JST-PRESTO (Japan)

PS-13-12
Photoelectrochemical Properties of Wurtzite Gallium Phosphide Nanowires grown on GaP (111)B substrates

°K. Tateno^{1,2}, Y. Ono³, K. Kumakura¹, ¹NTT BRL (Japan), ²NTT Nanophotonics Center (Japan), ³NTT Device Tech. Labs. (Japan)

PS-13-13
Improvement of Silicon Nanowire Solar Cells Made by Metal Catalyzed Electroless Etching and Nano-imprint Lithography

°J. Chen^{1,2}, T. Subramani¹, W. Jevasuwan¹, N. Fukata^{1,2}, ¹NIMS (Japan), ²Univ. of Tsukuba (Japan)

PS-13-14
Photocatalytic Performance of Multi-Morphological Nb-doped TiO₂ Nanofibers

°T.H. Lin¹, K.C. Hsiao¹, J.S. Chih¹, P.Y. Wu¹, T.F. Lin¹, M.C. Wu^{1,2}, ¹Chang Gung Univ. (Taiwan), ²Chang Gung Memorial Hospital (Taiwan)

PS-13-15(Late News)
First-Principles Device Simulations of All Two-Dimensional Material Tunneling Field-Effect Transistors

°M. Ohfuchi¹, T. Ozaki², ¹Fujitsu Labs. Ltd. (Japan), ²Univ. of Tokyo (Japan)

14: Power Devices and Materials (19 papers)

PS-14-01
Drain-Extended FinFET Technology for RF Power Applications

°B.Y. Chen^{1,2}, K.M. Chen¹, C.S. Chiu¹, G.W. Huang^{2,2}, H.C. Chen¹, C.C. Chen¹, F.K. Hsueh¹, M.C. Chen¹, E.Y. Chang², ¹National Nano Device Labs. (Taiwan), ²NCTU (Taiwan)

PS-14-02
Design and Characterization of Logic Compatible Drain Extended FinFETs for Embedded High-Voltage Circuits

H.H. Chen¹, °S.H. Shih¹, Y.C. King¹, C.J. Lin¹, ¹National Tsing Hua Univ. (Taiwan)

PS-14-03
Impact of the 3D Stacking Power Supply on Chip for High Frequency DC-DC Converter

°K. Hiura¹, Y. Ikeda¹, Y. Hino¹, S. Matsumoto¹, ¹Kyushu Inst. of Tech. (Japan)

PS-14-04
Comparisons of Hot-carrier Effects of Scaled N-Channel and P-Channel Thin-Film SOI Power MOSFETs under Constant Drain Electric Field

°K. Ikeno¹, S. Matsumoto¹, ¹Kyushu Inst. of Tech. (Japan)

PS-14-05
AC Hot Carrier Effect of the Thin-Film SOI Power n-MOSFET

°D. Takenaka¹, S. Matsumoto¹, ¹Kyushu Inst. of Tech. (Japan)

PS-14-06
Performance Enhancement of Bipolar Devices with Slot Pattern RESURF Approach in 40V BCD Technology

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PS-14-07
Ohmic Contact on N-type and P-type Ion-implanted 4H-SiC with Low-temperature Silicide-less Process

°H. Shimizu¹, A. Shima¹, Y. Shimamoto¹, ¹Hitachi, Ltd. (Japan)

PS-14-08
A Surface-Potential-Based Reverse-Transfer Capacitance Model for Vertical SiC DMOSFET

°M. Shintani¹, Y. Nakamura¹, M. Hiromoto¹, T. Hikihara¹, T. Sato¹, ¹Kyoto Univ. (Japan)

PS-14-09

Oxidation Mechanism of 4H-SiC in Dilute N₂O Ambient

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PS-14-10

Enhanced Thermal Oxidation of 4H-SiC Using SrTi_{1-x}Mg_xO_{3-δ} Catalyst

°L. Li¹, A. Ikeda¹, T. Asano¹, ¹Kyushu Univ. (Japan)

PS-14-11

Characterization of Electrical Field Enhancement at the Edge of Schottky Electrode on Diamond

°H. Umezawa^{1,2}, H. Gima³, K. Driche^{2,4}, Y. Kato¹, F. Donatini², E. Gheeraert², T. Yoshitake³, Y. Mokuno¹, ¹AIST (Japan), ²Inst. Néel / CNRS (France), ³Kyushu Univ. (Japan), ⁴Univ. of Tsukuba (Japan)

PS-14-12

Defect Reduction in Homoepitaxial Diamond Films for High Breakdown Voltage Schottky Diodes

°T. Teraji¹, H. Umezawa², ¹NIMS (Japan), ²AIST (Japan)

PS-14-13

Effect of Substrate Finish on Microstructure Evolution of Sintered Ag Joints to Attach Power Devices with Paste of Ag Nanoparticles during Isothermal Ageing

°Y. Wang^{1,2}, J. Li², P. Agyakwa², C. Johnson², S. Li², ¹China Aero-Polytechnology Establishment (China), ²Univ. of Nottingham (UK)

PS-14-14(Late News)

Impact of Optical Phonon Scattering on Inversion Channel Mobility in 4-H-SiC Trenched MOSFETs

°K. Kutsuki^{1,2}, S. Kawaji¹, Y. Watanabe¹, T. Onishi², H. Fujiwara², K. Yamamoto³, T. Yamamoto³, ¹Toyota Central R&D Labs. Inc. (Japan), ²TOYOTA MOTOR Corp. (Japan), ³DENSO Corp. (Japan)

PS-14-15(Late News)

Strong Impact of Slight Misalignment of the Trench Direction from [11-20] on Deep Trench Filling Epitaxy for SiC Super-junction (SJ) Devices

°R. Kosugi¹, S. Ji¹, K. Mochizuki¹, H. Kouketsu¹, Y. Kawada¹, H. Fujisawa¹, K. Kojima¹, S. Yoshida¹, Y. Yonezawa¹, H. Okumura¹, ¹AIST (Japan)

PS-14-16(Late News)

Effect of N Bonding Structure in AlON on Leakage Current of 4H-SiC MOS Capacitor

°W. Takeuchi¹, K. Yamamoto², T. Mimura², M. Sakashita¹, T. Kanemura², O. Nakatsuka¹, S. Zaima¹, ¹Nagoya Univ. (Japan), ²DENSO Corp. (Japan)

PS-14-17(Late News)

Simulation-based Study on the Optical Beam Intensity Dependence of the Optically Triggered 4H-SiC Thyristors Turn-on Operation

°J. Hasegawa¹, L. Pace², L.V. Phung², M. Hatano¹, D. Planson², ¹Tokyo Tech (Japan), ²Lab. Ampère (France)

PS-14-18(Late News)

4H-SiC Bipolar SRAM Cell for High-temperature Applications

H. Elgabra¹, °A. Siddiqui¹, S. Singh¹, ¹Khalifa Univ. of Science Tech. and Research (United Arab Emirates)

PS-14-19(Late News)

Characterization of Breakdown Behavior of Diamond SBDs using Impact Ionization Coefficients

°K. Driche^{1,2,3,4}, H. Umezawa^{1,2,4}, G. Chicot^{1,5}, N. Rouger^{1,5}, E. Gheeraert^{1,2,3}, ¹Univ. Grenoble Alpes (France), ²CNRS, Inst. Neel (France), ³Univ. of Tsukuba (Japan), ⁴AIST (Japan), ⁵CNRS, G2Elab (France)

15: Photovoltaic Materials and Devices

(12 papers)

PS-15-01

Non-Sulfurized CZTS (Cu₂ZnSnS₄) Thin Film Developed by Chemical Bath Deposition

°S. Lin¹, S. Chang¹, T. Hsueh², C. Lin¹, S. Chen¹, ¹National Cheng Kung Univ. (Taiwan), ²National Nano Device Labs. (Taiwan), ³National Yunlin Univ. of Sci. and Tech. (Taiwan)

PS-15-02

First-principles Study of Defect Formation in Photovoltaic Semiconductor Cu₂GeS₃

°H. Nishihara¹, T. Maeda¹, A. Shigemitsu¹, T. Wada¹, ¹Ryukoku Univ. (Japan)

PS-15-03

Study of Post-growth Se-annealing on the Properties of CuGaSe₂ layers Grown by Three-stage Evaporation Process

°M. Islam¹, A. Uedono¹, T. Sakurai¹, C. Hugenschmidt², W. Egger³, R. Scheer⁴, A. Dalla⁴, R. Krause-Rehberg⁴, K. Akimoto¹, ¹Univ. of Tsukuba (Japan), ²Tech. Univ. Munchen (Germany), ³Univ. der Bundeswehr München (Germany), ⁴Martin Luther Univ. Halle (Germany)

PS-15-04

Metalloporphyrin Doped Zinc Oxide Films for Flexible ZnO-based Dye-sensitized Solar Cell Application

°M. Haque Choudhury^{1,2}, A. Abuelwafa^{1,3}, N. Kishi¹, T. Soga¹, ¹Nagoya Inst. of Tech. (Japan), ²International Islamic Univ. Chittagong (Bangladesh), ³South Valley Univ. (Egypt)

PS-15-05

Withdrawn

PS-15-06

Fabrication, Characterization and Photovoltaic Properties of CH₃NH₃PbI₃ nanoparticles

°M. Shahiduzzaman¹, K. Yamamoto¹, Y. Furumoto¹, T. Kuwabara¹, K. Takahashi¹, T. Taima¹, ¹Kanazawa Univ. (Japan)

PS-15-07

Interfacial Layers for Thick Vacuum-deposited Crystalline Organic Photovoltaic Cells

°M. Katayama¹, T. Kaji¹, ¹Tokyo Univ. of Agri. & Tech. (Japan)

PS-15-08(Late News)

The Influence of Substrate Orientation on Localized Nitrogen State in GaAsN films Grown on Vicinal GaAs (001) Substrates

°M. Horikiri¹, W. Ding¹, Y. Yokoyama¹, H. Suzuki¹, T. Ikari¹, Y. Ohshita², M. Yamaguchi², A. Fukuyama¹, ¹Univ. of Miyazaki (Japan), ²Toyota Tech. Inst. (Japan)

PS-15-09(Late News)

KF Addition to Cu₂SnS₃ Thin Films Prepared by Sulfurization Process

°M. Nakashima¹, J. Fujimoto¹, T. Yamaguchi¹, J. Sasano², M. Izaki², ¹National Inst. of Tech., Wakayama College (Japan), ²Toyohashi Univ. of Tech. (Japan)

PS-15-10(Late News)

Effects of Se Flow Rates on Characteristics of CIGS Photovoltaics Devices Prepared by Two-step Process in Vacuum

°C. Huang¹, W. Chuang¹, C. Lin¹, ¹National Dong Hwa Univ. (Taiwan)

PS-15-11(Late News)

Stability and Performance Enhancement of Lead Iodide Perovskite Solar Cells using Salt Additives

°C. Chu¹, K. Karan¹, ¹Academia Sinica (Taiwan)

PS-15-12(Late News)

Microtextured Hybrid PEDOT:PSS-Silicon Solar Cells Employing Kirigami Graphene

°Z. Chen¹, Y. Lai¹, C. Huang², P. Yu¹, ¹NCTU (Taiwan), ²Ming Chi Univ. of Tech. (Taiwan)